RENESAS

RC191xx

PCIe Gen7 1.8V Fanout Buffer Family with LOS

The RC191xx (RC19108, RC19104, and RC19102) ultra-high performance fanout buffers support PCIe Gen1-7. They provide a Loss-Of-Signal (LOS) output for system monitoring and redundancy. The devices also incorporate Power Down Tolerant (PDT) and Flexible Startup Sequencing (FSS) features, easing system design. They can drive both sourceterminated and double-terminated loads, operating up to 400MHz.

The family offers 2, 4, or 8 Low-Power (LP) HCSL output pairs in 3×3 , 4×4 , and 5×5 mm packages. The RC191xx devices offer higher output counts in smaller packages compared to earlier buffer families. The buffers support both Common Clock (CC) and Independent Reference (IR) PCIe clock architectures.

Applications

- Cloud/High-performance computing
- nVME storage
- **Networking**
- AI Accelerators

Features

- PCIe Gen5 additive phase jitter: 5.9fs RMS
- PCIe Gen6 additive phase jitter: 3.5fs RMS
- PCIe Gen7 additive phase jitter: 2.4fs RMS
- DB2000Q additive phase jitter: 10fs RMS
- 12kHz to 20MHz additive phase jitter: 33fs RMS at 156.25MHz
- Power Down Tolerant (PDT) inputs
- Flexible Startup Sequencing (FSS)
- Automatic Clock Parking (ACP) upon loss of CLKIN
- Spread-spectrum tolerant
- CLKIN accepts HCSL or LVDS signal levels
- -40 to $+105$ °C, 1.8V ± 5% operation
- Devices provide:
	- Pin or SMBus selectable 33Ω, 85Ω, or 100Ω differential output impedance
	- Pin or SMBus selectable output slew rate
	- Pin or SMBus selectable output amplitude
	- 9 SMBus addresses plus write protection

Figure 1. RC191xx Block Diagram

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1. Pin Information

1.1 Signal Types

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1.2.2 RC19108 Pin Descriptions

Table 1. RC19108 Pin Descriptions

Table 1. RC19108 Pin Descriptions (Cont.)

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1.3.1 RC19108A001 Pin Assignments

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1.4.2 RC19104 Pin Descriptions

Table 3. RC19104 Pin Descriptions

Table 3. RC19104 Pin Descriptions (Cont.)

1.5 RC19104A001 Pin Information

1.5.1 RC19104A001 Pin Assignments

Figure 5. RC19104A100 28-VFQFPN – Top View

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Table 4. RC19104A100 Pin Descriptions

1.6 RC19102 Pin Information

1.6.1 RC19102 Pin Assignments

1.6.2 RC19102 Pin Descriptions

Table 5. RC19102 Pin Descriptions

2. Specifications

2.1 Absolute Maximum Ratings

Table 6. Absolute Maximum Ratings

1. Inputs not designated Power Down Tolerant (PDT) in the pin description tables.

2. Inputs designated Power Down Tolerant (PDT) in the pin description tables.

3. The V_{PUP} voltage may be applied before main VDD is applied. The LOSb pin is PDT to this voltage, not to 3.6V.

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Table 8. Thermal Characteristics

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2.3.1 Phase Jitter

Table 9. PCIe Refclk Phase Jitter - Normal Conditions [1][2][3]

1. The Refclk jitter is measured after applying the filter functions found in the *PCI Express Base Specification 7.0, Revision 0.7*. For the exact measurement setup, see [Test Loads.](#page-28-0) The worst case results for each data rate are summarized in this table. Equipment noise is removed from all measurements.

- 2. Jitter measurements are made with a capture of at least 100,000 clock cycles captured by a real-time oscilloscope (RTO) with a sample rate of 20GS/s or greater. Broadband oscilloscope noise must be minimized in the measurement. The measured PP jitter is used (no extrapolation) for RTO measurements. Alternately, jitter measurements can be made with a Phase Noise Analyzer (PNA) extending (flat) and integrating and folding the frequency content up to an offset from the carrier frequency of at least 200MHz (at 300MHz absolute frequency) below the Nyquist frequency. For PNA measurements for the 2.5GT/s data rate, the RMS jitter is converted to peak-to-peak jitter using a multiplication factor of 8.83.
- 3. Differential input swing ≥ 1600mV and input slew rate ≥ 3.5V/ns. The rms sum of the source jitter and the additive jitter (arithmetic sum for PCIe Gen1) must be less than the jitter specification listed
- 4. SSC spurs from the fundamental and harmonics are removed up to a cutoff frequency of 2MHz taking care to minimize removal of any non-SSC content.
- 5. Note that 0.7ps RMS is to be used in channel simulations to account for additional noise in a real system.
- 6. Note that 0.25ps RMS is to be used in channel simulations to account for additional noise in a real system.
- 7. Note that 0.15ps RMS is to be used in channel simulations to account for additional noise in a real system.
- 8. Note that 0.10ps RMS is to be used in channel simulations to account for additional noise in a real system.
- 9. The *PCI Express Base Specification 7.0. Revision 0.7* provides the filters necessary to calculate SRIS jitter values; it does not provide specification limits, therefore, the reference to this footnote in the Limit column. SRIS values are informative only. A common practice is to split the common clock budget in half. For 16GT/s data rates and above, the user must choose whether to use the output jitter specification, or the input jitter specification, which includes an allocation for the jitter added by the channel. Using 32GT/s, the Refclk jitter budget is 150fs RMS. One half of the Refclk jitter budget is 106fs RMS. At the clock input, the system must deliver 250fs RMS. One half of this value is 177fs RMS. If the clock is placed next to the PCIe device in an SRIS system, the channel is very short and the user can choose to use this more relaxed value as the jitter limit.

Table 10. PCIe Refclk Phase Jitter - Degraded Conditions [1][2][3]

1. The Refclk jitter is measured after applying the filter functions found in the *PCI Express Base Specification 7.0, Revision 0.7*. For the exact measurement setup, see [Test Loads.](#page-28-0) The worst case results for each data rate are summarized in this table. Equipment noise is removed from all measurements.

2. Jitter measurements are made with a capture of at least 100,000 clock cycles captured by a real-time oscilloscope (RTO) with a sample rate of 20GS/s or greater. Broadband oscilloscope noise must be minimized in the measurement. The measured PP jitter is used (no extrapolation) for RTO measurements. Alternately, jitter measurements can be made with a Phase Noise Analyzer (PNA) extending (flat) and integrating and folding the frequency content up to an offset from the carrier frequency of at least 200MHz (at 300MHz absolute frequency) below the Nyquist frequency. For PNA measurements for the 2.5GT/s data rate, the RMS jitter is converted to peak-to-peak jitter using a multiplication factor of 8.83.

3. Differential input swing ≥ 1600mV and input slew rate ≥ 3.5V/ns. The rms sum of the source jitter and the additive jitter (arithmetic sum for PCIe Gen1) must be less than the jitter specification listed.

4. SSC spurs from the fundamental and harmonics are removed up to a cutoff frequency of 2MHz taking care to minimize removal of any non-SSC content.

5. Note that 0.7ps RMS is to be used in channel simulations to account for additional noise in a real system.

- 6. Note that 0.25ps RMS is to be used in channel simulations to account for additional noise in a real system.
- 7. Note that 0.15ps RMS is to be used in channel simulations to account for additional noise in a real system.

8. Note that 0.10ps RMS is to be used in channel simulations to account for additional noise in a real system.

9. The *PCI Express Base Specification 7.0, Revision 0.7* provides the filters necessary to calculate SRIS jitter values; it does not provide specification limits, therefore, the reference to this footnote in the Limit column. SRIS values are informative only. A common practice is to split the common clock budget in half. For 16GT/s data rates and above, the user must choose whether to use the output jitter specification, or the input jitter specification, which includes an allocation for the jitter added by the channel. Using 32GT/s, the Refclk jitter budget is 150fs RMS. One half of the Refclk jitter budget is 106fs RMS. At the clock input, the system must deliver 250fs RMS. One half of this value is 177fs RMS. If the clock is placed next to the PCIe device in an SRIS system, the channel is very short and the user can choose to use this more relaxed value as the jitter limit.

Table 11. Non-PCIe Refclk Phase Jitter [1][2][3]

1. See [Test Loads](#page-28-0) for test configuration.

2. SMA100B used as signal source.

3. The RC19xxx devices meet all legacy QPI/UPI specifications by meeting the PCIe and DB2000Q specifications listed in this document.

4. Differential input swing = 1,600mV and input slew rate = 3.5V/ns.

5. The rms sum of the source jitter and the additive jitter (arithmetic sum for PCIe Gen1) must be less than the jitter specification listed.

6. Differential input swing = 800mV and input slew rate = 1.5V/ns.

2.3.2 Output Frequencies, Startup Time, and LOS Timing

Table 12. Output Frequencies, Startup Time, and LOS Timing

1. Measured from when all power supplies have reached > 90% of nominal voltage to the first stable clock edge on the output. PWRGD_PWRDNb tied to VDD in this case.

2. VDD stable, measured from de-assertion of PWRGD_PWRDNb.

3. The clock detect circuit does not qualify the accuracy of the input clock. The first input clock must appear to release the power on reset and enable the LOS circuit at power up.

4. PWRGD_PWRDNb high. The Automatic Clock Parking (ACP) circuit - if enabled - will park the outputs in a low/low state within this time. See Byte4, bit 4, LOSb_ACP_ENABLE.

5. PWRGD_PWRDNb high. The device will drive the outputs to a high/low state within this time and then begin clocking the outputs.

2.3.3 CLK AC/DC Output Characteristics

Table 13. 85Ω CLK AC/DC Characteristics – Source-Terminated 100MHz PCIe Applications [1]

1. Standard high impedance load with $C_1 = 2pF$. For more information, see [Figure](#page-28-1) 9, ZOUTSEL_tri = 0.

2. The specification limits are taken from either the *PCIe Base Specification Revision 6.0* or from relevant x86 processor specifications, whichever is more stringent.

3. Measured from single-ended waveform.

- 4. Defined as the maximum instantaneous voltage including overshoot.
- 5. Defined as the minimum instantaneous voltage including undershoot.

6. Measured at crossing point where the instantaneous voltage value of the rising edge of REFCLK+ equals the falling edge of REFCLK-.

7. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.

8. Defined as the total variation of all crossing voltages of Rising REFCLK+ and Falling REFCLK-. This is the maximum allowed variance in VCROSS for any particular system.

9. Measured from differential waveform.

10. Measured from -150mV to +150mV on the differential waveform (derived from REFCLK+ minus REFCLK-). The signal must be monotonic through the measurement region for rise and fall time. The 300mV measurement window is centered on the differential zero crossing.

11. Matching applies to rising edge rate for REFCLK+ and falling edge rate for REFCLK-. It is measured using a ±75mV window centered on the median cross point where REFCLK+ rising meets REFCLK- falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations. The Rise Edge Rate of REFCLK+ should be compared to the Fall Edge Rate of REFCLK-; the maximum allowed difference should not exceed 20% of the slowest edge rate.

Table 14. 100Ω CLK AC/DC Characteristics – Source-Terminated 100MHz PCIe Applications [1]

1. Standard high impedance load with C_L = 2pF. For more information, see [Figure](#page-28-1) 9, ZOUTSEL_tri = 1.

2. The specification limits are taken from either the *PCIe Base Specification Revision 6.0* or from relevant x86 processor specifications, whichever is more stringent.

- 3. Measured from single-ended waveform.
- 4. Defined as the maximum instantaneous voltage including overshoot.
- 5. Defined as the minimum instantaneous voltage including undershoot.
- 6. Measured at crossing point where the instantaneous voltage value of the rising edge of REFCLK+ equals the falling edge of REFCLK-.

7. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.

- 8. Defined as the total variation of all crossing voltages of Rising REFCLK+ and Falling REFCLK-. This is the maximum allowed variance in VCROSS for any particular system.
- 9. Measured from differential waveform.
- 10. Measured from -150mV to +150mV on the differential waveform (derived from REFCLK+ minus REFCLK-). The signal must be monotonic through the measurement region for rise and fall time. The 300mV measurement window is centered on the differential zero crossing.
- 11. Matching applies to rising edge rate for REFCLK+ and falling edge rate for REFCLK-. It is measured using a ±75mV window centered on the median cross point where REFCLK+ rising meets REFCLK- falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations. The Rise Edge Rate of REFCLK+ should be compared to the Fall Edge Rate of REFCLK-; the maximum allowed difference should not exceed 20% of the slowest edge rate.

Table 15. 85ohm CLK AC/DC Characteristics – Source-Terminated, Non-PCIe Applications [1]

1. Standard high impedance load with C_1 = 2pF. For more information, see [Figure](#page-28-1) 9, ZOUTSEL tri = 0.

2. Measured from single-ended waveform.

3. Measured at crossing point where the instantaneous voltage value of the rising edge of CLK equals the falling edge of CLKb.

4. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.

5. Defined as the total variation of all crossing voltages of Rising CLK and Falling CLKb. This is the maximum allowed variance in VCROSS for any particular system.

6. Measured from differential waveform.

Table 16. 85ohm CLK AC/DC Characteristics – Double-Terminated, Non-PCIe Applications [1]

1. Both Tx and Rx are terminated (double-terminated) with $C_L = 2pF$. This reduces amplitude by 50%. For more information, see [Figure](#page-28-2) 10, Z OUTSEL tri = 0.

- 2. Measured from single-ended waveform.
- 3. Measured at crossing point where the instantaneous voltage value of the rising edge of CLK equals the falling edge of CLKb.
- 4. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.
- 5. Defined as the total variation of all crossing voltages of Rising CLK and Falling CLKb. This is the maximum allowed variance in VCROSS for any particular system.
- 6. Measured from differential waveform.

Table 17. 100ohm CLK AC/DC Characteristics – Source-Terminated, Non-PCIe Applications [1]

1. Standard high impedance load with $C_1 = 2pF$. For more information, see [Figure](#page-28-1) 9, ZOUTSEL_tri = 1.

2. Measured from single-ended waveform.

3. Measured at crossing point where the instantaneous voltage value of the rising edge of CLK equals the falling edge of CLKb.

4. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.

5. Defined as the total variation of all crossing voltages of Rising CLK and Falling CLKb. This is the maximum allowed variance in VCROSS for any particular system.

6. Measured from differential waveform.

1. Both Tx and Rx are terminated (double-terminated) with $C_1 = 2pF$. This reduces amplitude by 50%. For more information, see [Figure](#page-28-2) 10, ZOUTSEL_tri = 1.

2. Measured from single-ended waveform.

3. Measured at crossing point where the instantaneous voltage value of the rising edge of CLK equals the falling edge of CLKb.

4. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.

5. Defined as the total variation of all crossing voltages of Rising CLK and Falling CLKb. This is the maximum allowed variance in VCROSS for any particular system.

6. Measured from differential waveform.

Table 19. 34ohm CLK AC/DC Characteristics - Rx-Terminated, Non-PCIe Applications [1]

1. ZOUTSEL_tri = M. This setting turns off the source termination, provided approximately 75% of the source-terminated amplitude at the receiver with C_1 = 2pF. For more information, see [Figure](#page-28-2) 10,

2. Measured from single-ended waveform.

3. Measured at crossing point where the instantaneous voltage value of the rising edge of CLK equals the falling edge of CLKb.

4. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.

5. Defined as the total variation of all crossing voltages of Rising CLK and Falling CLKb. This is the maximum allowed variance in VCROSS for any particular system.

6. Measured from differential waveform.

2.3.4 CLKIN AC/DC Characteristics

Table 20. CLKIN AC/DC Characteristics

| Symbol | Parameter | Condition | Minimum ^[1] | Typical | Maximum | Unit |
|--------------------|-------------------------|--|--------------------------|--------------------------|----------------|------|
| VIHMAX | Maximum Input Voltage | Single-ended value. | $\overline{}$ | $\overline{}$ | 1.2 | V |
| V _{CROSS} | Input Crossover Voltage | Lo/Lo Detect Disabled. | 100 | \blacksquare | | mV |
| | | Lo/Lo Detect Enabled. | 131 | \blacksquare | | mV |
| V _{SWING} | Input Swing | Differential value. Lo/Lo Detect Disabled. | 200 | $\overline{}$ | | mV |
| | | Differential value. Lo/Lo Detect Enabled. | 528 | | | mV |
| dv/dt | Input Slew Rate | Measured differentially. [2] Lo/Lo Detect Disabled. | 0.6 | | | V/ns |

1. For values required for performance, see the [Phase Jitter](#page-14-1) tables.

2. Measured from -150mV to +150mV on the differential waveform (derived from REFCLK+ minus REFCLK-). The signal must be monotonic through the measurement region for rise and fall time. The 300mV measurement window is centered on the differential zero-crossing.

Figure 7. Clock Input Bias Network

2.3.5 Output-to-Output and Input-to-Output Skew

Table 21. Output-to-Output and Input-to-Output Skew [1]

1. These parameters are measured with the loads in [Figure](#page-28-2) 10.

2. This parameter is defined in accordance with JEDEC Standard 65.

3. Defined as the time between to output rising edge and the input rising edge that caused it.

2.3.6 I/O Electrical Characteristics

Table 22. I/O Electrical Characteristics

| Symbol | Parameter | Condition | Minimum | Typical | Maximum | Unit |
|-----------------|---|---|-----------------------------|--------------------------|-----------------------------|-----------|
| V_{IH} | Input High Voltage [1][2] | Single-ended inputs, unless otherwise listed. | $0.65 \times$ VDD | | $VDD + 0.3$ | \vee |
| V_{IL} | Input Low Voltage [1][2] | | -0.3 | $\overline{}$ | $0.35 \times$ VDD | \vee |
| V_{IH} | Input High Voltage | | $0.75 \times$ VDD | | $VDD + 0.3$ | \vee |
| V_{IM} | Input Mid Voltage | SADR_tri[1:0]. | $0.45 \times$ VDD | $0.5 \times VDD$ | $0.55 \times$ VDD | V |
| V_{IL} | Input Low Voltage | | -0.3 | | $0.25 \times$ VDD | \vee |
| V_{OL} | Output Low Voltage | LOSb, I_{OL} = 2mA. | \overline{a} | 0.1 | 0.4 | \vee |
| | | CLKIN | $\,$ 5 $\,$ | $\overline{}$ | 15 | μA |
| I_{IH} | Input Leakage Current High, V_{IN} = VDD | CLKIN_b | -3 | $\overline{}$ | $+3$ | |
| | | PWRGD PWRDNb | -35 | \overline{a} | -20 | |
| | | SADR tri[1:0] | 25 | $\overline{}$ | 35 | |
| | | Single-ended inputs not otherwise listed | 25 | $\overline{}$ | 35 | |
| | Input Leakage Current Low, $V_{IN} = 0V$ | CLKIN | -3 | $\overline{}$ | $+3$ | μA |
| | | CLKIN_b | -12 | $\overline{}$ | -6 | |
| ΙL. | | PWRGD PWRDNb | -35 | $\overline{}$ | -20 | |
| | | SADR tri[1:0] | -35 | \overline{a} | -20 | |
| | | Single-ended inputs not otherwise listed | -35 | $\overline{}$ | -20 | |
| Rp | PD_CLKIN | Value of internal pull-down resistor to ground (CLKIN) | \overline{a} | 53 | $\overline{}$ | |
| | PU CLKINb | Value of internal pull-up resistor to 0.5V (CLKINb). | \overline{a} | 57 | \mathbf{r} | $k\Omega$ |
| | Pull-up/Pull-down Resistor | Single-ended inputs. | ٠ | 125 | $\overline{}$ | |
| | Output Impedance | $CLK/CLKb$ single-ended impedance, 85Ω setting | L, | 34 | $\overline{}$ | Ω |
| Zo | | CLK/CLKb single-ended impedance, 100Ω setting | \overline{a} | 39 | \blacksquare | |
| | | $CLK/CLKb$ single-ended impedance, 33Ω setting | $\overline{}$ | 14 | $\overline{}$ | |

1. For SCLK and SDATA, see the [SMBus DC Electrical Characteristics](#page-26-1) table.

2. These values are compliant with JESD8-7A 1.8V Normal Range.

2.3.7 Power Supply Current

Table 23. Power Supply Current [1][2][3]

| Symbol | Parameter | Condition | Minimum | Typical | Maximum | Unit |
|----------------|---|---|----------------|----------------|----------------|------|
| I DDCLK | $V_{\text{DDCI K}}$ Operating Current - RC19108, 85Ω impedance | Fast slew rate, source-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 76 | 79 | |
| | | Fast slew rate, double-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 88 | 89 | |
| | | Fast slew rate, source-terminated load at maximum output frequency. PWRGD_PWRDNb = 1. | | 95 | 100 | mA |
| | | Fast slew rate, double-terminated load at maximum output frequency. PWRGD_PWRDNb = 1. | | 115 | 121 | |
| I DDCLK | V _{DDCLK} Operating Current- RC19104, 85Ω impedance | Fast slew rate, source-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 45 | 47 | mA |
| | | Fast slew rate, double-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 51 | 52 | |
| | | Fast slew rate, source-terminated load at maximum output frequency. PWRGD_PWRDNb = 1. | | 51 | 60 | |
| | | Fast slew rate, double-terminated load at maximum output frequency. PWRGD_PWRDNb = 1. | | 58 | 71 | |
| I DDCLK | V _{DDCLK} Operating Current- RC19102, 85 Ω impedance | Fast slew rate, source-terminated load at 100MHz. (RC19102 is always powered up when VDD is applied.) | | 30 | 30 | |
| | | Fast slew rate, double-terminated load at 100MHz. (RC19102 is always powered up when VDD is applied.) | | 33 | 33 | |
| | | Fast slew rate, source-terminated load at maximum output frequency. (RC19102 is always powered up when VDD is applied.) | | 39 | 41 | mA |
| | | Fast slew rate, double-terminated load at maximum output frequency. (RC19102 is always powered up when VDD is applied.) | | 44 | 46 | |
| | V _{DDCLK} Operating Current – RC19108, 100 Ω impedance | Fast slew rate, source-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 73 | 79 | |
| | | Fast slew rate, double-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 88 | 98 | |
| I DDCLK | | Fast slew rate, source-terminated load at maximum output frequency. PWRGD PWRDNb = 1. | | 100 | 105 | mA |
| | | Fast slew rate, double-terminated load at maximum output frequency. PWRGD_PWRDNb = 1. | | 116 | 120 | |
| I DDCLK | V _{DDCLK} Operating Current- RC19104, 100 Ω impedance | Fast slew rate, source-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 44 | 47 | |
| | | Fast slew rate, double-terminated load at 100MHz. PWRGD_PWRDNb = 1. | | 53 | 59 | |
| | | Fast slew rate, source-terminated load at maximum output frequency. PWRGD_PWRDNb = 1. | | 53 | 63 | mA |
| | | Fast slew rate, double-terminated load at maximum output frequency. PWRGD_PWRDNb = 1. | | 60 | 71 | |

Table 23. Power Supply Current [1][2][3] (Cont.)

1. For more information, see [Test Loads](#page-28-0).

2. Output voltage set to 800mV. Slew rate has negligible effect on current consumption, so only fast is listed.

3. Total operating current is obtained by adding IDDCLK + IDDDIG. Power down current is obtained by adding IDDCLK_PD + IDDDIG_PD.

2.3.8 SMBus Electrical Characteristics

This section applies to all devices except the RC19102 because the RC19102 does not have an SMBus interface.

| Symbol | Parameter | Condition | Minimum | Typical | Maximum | Unit |
|------------------|--|------------------|----------------|----------------|----------------|------|
| V_{IH} | High-level Input Voltage for SMBCLK and SMBDAT | $VDD = 1.8V$ | 0.8 VDD | | 3.4 | |
| V_{IL} | Low-level Input Voltage for SMBCLK and SMBDAT | $VDD = 1.8V$ | | | 0.3 VDD | |
| V _{HYS} | Hysteresis of Schmitt Trigger Inputs | | 0.05 VDD | | | |
| V_{OL} | Low-level Output Voltage for SMBCLK and SMBDAT | I_{OL} = 4mA | | 0.28 | 0.4 | |
| ^I IN | Input Leakage Current per Pin | | $[2]$ | | $[2]$ | μA |
| C_B | Capacitive Load for Each Bus Line | | | | 400 | pF |

Table 24. SMBus DC Electrical Characteristics [1]

1. V_{OH} is governed by the V_{PUP}, the voltage rail to which the pull-up resistors are connected. The maximum V_{PUP} voltage is 3.6V.

2. See [I/O Electrical Characteristics.](#page-23-2)

Figure 8. SMBus Slave Timing Diagram

1. Power must be applied and PWRGD_PWRDNb must be a 1 for the SMBus to be active.

- 2. A master should not drive the clock at a frequency below the minimum f_{SMB}. Further, the operating clock frequency should not be reduced below the minimum value of fSMB due to periodic clock extending by slave devices as defined in Section 5.3.3 of System Management Bus (SMBus) Specification, Version 3.1, dated 19 Mar 2018. This limit does not apply to the bus idle condition, and this limit is independent from the t_{LOW: SEXT} and $t_{LOW: MEXT}$ limits. For example, if the SMBCLK is high for $t_{HIGH, MAX}$, the clock must not be periodically stretched longer than $1/f_{SMB, MIN}$ t_{HIGH} MAX. This requirement does not pertain to a device that extends the SMBCLK low for data processing of a received byte, data buffering and so forth for longer than 100 us in a non-periodic way.
- 3. A device must internally provide sufficient hold time for the SMBDAT signal (with respect to the VIH,MIN of the SMBCLK signal) to bridge the undefined region of the falling edge of SMBCLK.
- 4. Slave devices may have caused other slave devices to hold SDA low. This is the maximum time that a device can hold SMBDAT low after the master raises SMBCLK after the last bit of a transaction. A slave device may detect how long SDA is held low and release SDA after the time out period.
- 5. Devices participating in a transfer can abort the transfer in progress and release the bus when any single clock low interval exceeds the value of t_{TIMEOUT,MIN}. After the master in a transaction detects this condition, it must generate a stop condition within or after the current data byte in the transfer process. Devices that have detected this condition must reset their communication and be able to receive a new START condition no later than t_{TIMEOUT} MAX. Typical device examples include the host controller, and embedded controller, and most devices that can master the SMBus. Some simple devices do not contain a clock low drive circuit; this simple kind of device typically may reset its communications port after a start or a stop condition. A timeout condition can only be ensured if the device that is forcing the timeout holds the SMBCLK low for t_{TIMEOUT}, MAX or longer.
- 6. The device has the option of detecting a timeout if the SMBDATA pin is also low for this time.
- 7. t_{HIGH,MAX} provides a simple guaranteed method for masters to detect bus idle conditions. A master can assume that the bus is free if it detects that the clock and data signals have been high for greater than t_{HIGH,MAX}.
- 8. tLOW:MEXT is the cumulative time a master device is allowed to extend its clock cycles within each byte of a message as defined from STARTto-ACK, ACK-to-ACK, or ACK-to-STOP. It is possible that a slave device or another master will also extend the clock causing the combined clock low time to be greater than tLOW:MEXT on a given byte. This parameter is measured with a full speed slave device as the sole target of the master.
- 9. The rise and fall time measurement limits are defined as follows: Rise Time Limits: $(V_{\vert L:MAX} - 0.15 V)$ to $(V_{\vert H:MIN} + 0.15 V)$ Fall Time Limits: $(V_{H:MIN} + 0.15 V)$ to $(V_{H:MAX} - 0.15 V)$
- 10. Devices must provide a means to reject noise spikes of a duration up to the maximum specified value.

3. Test Loads

Figure 9. AC/DC Test Load for Differential Outputs (Standard PCIe Source-Terminated)

Figure 10. AC/DC Test Load for Differential Outputs (Double-Terminated or Receiver-Terminated)

1. This setting is designed to provide additional amplitude for receiver-terminated loads by turning off the source termination in the output driver. There is no reflection with receiver terminated loads since the receiver termination absorbs the incident waveform.

Figure 11. Test Load for PCIe Phase Jitter Measurements

Table 28. Parameters for PCIe Phase Jitter Measurements

1. PCIe Gen6 specifies L = 0cm for 32 and 64 GT/s. L = 25.4cm is more conservative.

4. General SMBus Serial Interface Information

This section applies to all device except the RC19102 which does not have an SMBus interface.

4.1 How to Write

- Controller (host) sends a start bit
- Controller (host) sends the write address
- Renesas clock will **acknowledge**
- Controller (host) sends the beginning byte Location $= N$
- Renesas clock will **acknowledge**
- **Controller (host) sends the byte count =** X
- Renesas clock will **acknowledge**
- Controller (host) starts sending Byte **N through Byte N+X-1**
- Renesas clock will **acknowledge** each byte one at a time
- Controller (host) sends a stop bit

4.2 How to Read

- Controller (host) will send a start bit
- Controller (host) sends the write address
- Renesas clock will **acknowledge**
- Controller (host) sends the beginning byte Location $= N$
- Renesas clock will **acknowledge**
- Controller (host) will send a separate start bit
- Controller (host) sends the read address
- Renesas clock will **acknowledge**
- **Renesas clock will send the data byte count =** X
- Renesas clock sends Byte **N+X-1**
- Renesas clock sends **Byte L through Byte X (if X(H) was written to Byte 7)**
- Controller (host) will need to acknowledge each byte
- Controller (host) will send a not acknowledge bit
- Controller (host) will send a stop bit

4.3 SMBus Bit Types

4.4 Write Lock Functionality

4.5 SMBus Address Decode

4.6 SMBus Registers

Table 29. Register Index

4.6.1 OUTPUT_ENABLE

Output Enable Register.

4.6.2 OEB_PIN_READBACK

OEb Pin Readback Register.

4.6.3 LOS_CONFIG

Loss of Signal and Async Mode Configuration Register.

4.6.4 VENDOR_REVISION_ID

Vendor ID, Revision ID Register.

4.6.5 DEVICE_ID

Device ID Register.

4.6.6 BYTE_COUNT

Number of Bytes Returned on an SMBus Block Read.

4.6.7 SLEW_AMP_SELECT

Multifunction Pin Configuration Register.

4.6.8 INPUT_PULLUP_PULLDOWN_4

Internal Pull-up / Pull-down Configuration Register.

4.6.9 AMP_CTRL_ALT

Alternate Amplitude Selection Register.

4.6.10 AMP_CTRL_DEF

Default Amplitude Selection Register.

4.6.11 PD_RESTORE_LOSb_CONFIG

Configuration and Status Register.

4.6.12 OUTPUT_IMPEDANCE_7_0

Output Impedance Select Register 0.

4.6.13 OUTPUT_REC_SEL_7_0

Output Impedance Select Register 1.

4.6.14 OUTPUT_SLEW_RATE_7_0

Output Slewrate Select Register.

4.6.15 LOW-LOW_DETECT

CLKIN Low-Low Detect Enable Register.

4.6.16 RECEIVER_CONTROL

CLKIN Configuration Register.

4.6.17 WRITE_LOCK

Non-Clearable Write Lock Register.

4.6.18 WRITE_LOCK_LOS_EVT

Clearable Write Lock and LOS Event Sticky Register.

5. Applications Information

5.1 Inputs, Outputs, and Output Enable Control

The CLKIN/CLKINb inputs of the RC191xx devices have an internal bias network that prevents self-oscillation from floating input clock condition.

5.1.1 Recommendations for Unused Inputs and Outputs

5.1.1.1 Unused Single-ended Control Inputs

The single-ended control pins have internal pull-up and/or internal pull-down resistors and do not require external resistors. They can be left floating if the default pin state is the desired state. If external resistors are needed to change the pin state or are desired for design robustness, 10kohm is the recommended value.

5.1.1.2 Unused Differential CLK Outputs

All unused CLK outputs can be left floating. Renesas recommends that no trace be attached to unused CLK outputs. While not required (but highly recommended), the best design practice is to disable unused CLK outputs. This is easily accomplished with the dedicated OEb pin for each output.

5.1.1.3 Unused SMBus Clock and Data Pins

If the SMBus interface is not used, the clock and data pins must be pulled high with an external resistor. The two pins can share a resistor if there is no possibility of using the SMBus interface for debug purposes. If the interface might be used for debug, separate resistors must be used. 10kohm is the recommended value. The SMBus pins are 3.3V tolerant and may be used with a 3.3V pull-up voltage.

5.1.2 Differential CLKIN Configurations

The RC191xx clock input buffer supports four configurations:

- Direct connection to HCSL-level clocks
- AC-coupled connection to LVDS-level clocks with *external* termination resistor
- Internal self-bias circuit for applications that *externally* AC-couple the input clock This feature is enabled by the **AC_IN** bit.
- Internal pull-down resistors (Rp) to terminate the clock input at the receiver. This feature is enabled by the **Rx_TERM** bit.

Devices with multiple input clocks have individual AC_IN and Rx_TERM configuration bits for each input. The internal input clock terminations prevent reflections and are useful for non-PCIe applications, where the frequency and transmission line length vary from the 100MHz PCIe standard.

The following table summarize the CLKIN configuration bit settings for the various configurations that are displayed in [Figure](#page-43-1) 12 to [Figure](#page-43-4) 15.

Figure 12. HCSL Input Levels (PCIe Standard) Figure 13. LVDS Input Levels

Figure 14. External AC-Coupling Figure 15. Receiver Termination

5.1.3 Differential CLK Output Configurations

5.1.3.1 Direct-Coupled HCSL Loads

The RC191xx LP-HCSL CLK outputs have internal source terminations and directly drive industry-standard HCSL-level inputs with no external components. They support both 85ohm and 100ohm differential impedances. The CLK outputs can also drive receiver-terminated HCSL loads. The combination of source termination and receiver termination results in a double-terminated load. When double-terminated, the CLK output swing will be half of the source-terminated values.

5.1.3.2 AC-Coupled non-HCSL Loads

The RC191xx CLK output can directly drive AC-coupling capacitors without any termination components. The clock input side of the AC-coupling capacitor may require an input-dependent bias network (BN). For examples of terminating the RC191xx CLK outputs to other logic families such as LVDS, LVPECL, or CML, see [A](https://www.renesas.com/us/en/document/apn/891-driving-lvpecl-lvds-cml-and-sstl-logic-idt-universal-low-power-hcsl-outputs)N-891.

[Figure](#page-43-5) 16 to [Figure](#page-44-2) 19 show the various CLK output configurations.

Figure 16. Direct-Coupled Source-Terminated HCSL (ZOUT_SEL_tri = 0 or 1)

Figure 17. Direct-Coupled Double-Terminated HCSL

Figure 18. Receiver-Terminated Load (ZOUT_SEL_tri = M)

Figure 19. AC-Coupled Non-PCIe Load

5.2 Power Down Tolerant Pins

Power Down Tolerant (PDT) pins can be driven even though VDD is not present (the device is not powered). There will be no ill effects to the device and it will power up normally. This feature supports disaggregation, where the RC191xx may be on one circuit board and devices that interface with it are on other boards. These boards may power up at different times, driving pins on the RC191xx before it has received power. See the pin descriptions to identify which pins are PDT. PDT pins are also 3.3V tolerant.

5.3 Flexible Startup Sequencing

RC191xx devices support Flexible Startup Sequencing (FSS). FSS allows application of CLKIN at different times in the device/system startup sequence. FSS is an additional feature that helps the system designer manage the impact of disaggregation. [Table](#page-44-3) 31 shows the supported sequences; that is, the RC191xx devices can have CLKIN running before VDD is applied, and can have VDD applied and sit for extended periods with no input clock.

5.4 Loss of Signal and Automatic Clock Parking

The RC191xx buffers and multiplexers have a Loss of Signal (LOS) circuit to detect the presence or absence of an input clock. The LOS circuit drives the open-drain LOSb pin (the "b" suffix indicates "bar", or active-low) and sets the LOS_EVT bit in the SMBus register space. CLKIN is represented differentially in [Figure](#page-45-3) 20.

[Figure](#page-45-3) 20 shows the LOSb de-assertion timing for the RC191xx clock buffers. LOSb defaults to low at power up.

Figure 20. LOSb De-assert Timing RC191xx Devices

The following diagram shows the LOSb assertion sequence when the CLKIN is lost. It also shows the Automatic Clock Parking (ACP) circuit bring the inputs to a Low/Low state after an LOS event. For exact timing, see [Electrical Specifications](#page-14-0).

Figure 21. LOSb Assert Timing

5.5 Output Enable Control

The RC191xx buffer family provides two mechanisms to enable or disable clock outputs. All three mechanisms start and stop the output clocks in a synchronous, glitch-free manner. A clock output is enabled only when all mechanisms indicate "enabled." The following sections describe the mechanisms.

5.5.1 SMBus Output Enable Bits

This section does not apply to the RC19102 because it does not have an SMBus.

The RC191xx clock buffer family has a traditional SMBus output enable bit for each output. The power-up default is 1, or enabled. Changing this bit to a 0 disables the output to a low/low state. The transitions between the enable and disable states are glitch-free in both directions.

Note: The glitch-free synchronization logic requires the CLKIN be running to enable or disable the outputs with this mechanism.

5.5.2 Output Enable (OEb) Pins

The OEb (Note: the "b" suffix indicates "bar", or active-low) pins on the RC191xx family provide flexible CLKREQb functionality for PCIe slots and/or banked OE control for 'motherboard-down' devices (depending on the device). If the OEb pin is low the controlled output is enabled. If the OEb pin is high, the controlled output is disabled to a low/low state. All OEb pins enable and disable the controlled outputs in a glitch-free, synchronous manner.

Note: The glitch-free synchronization logic requires the CLKIN be running to enable or disable the outputs with this mechanism.

6. Package Outline Drawings

The package outline drawings are located at the end of this document and are accessible from the Renesas website (see the package links in [Ordering Information](#page-47-0)). The package information is the most current data available and is subject to change without revision of this document.

7. Marking Diagrams

8. [Ordering Information](https://www.renesas.com/us/en/document/psc/ndndg28-package-outline-40-x-40-x-09-mm-body-vqpf-n-04-mm-ball-pitch)

9. Revision History

RENESAS

Package Outline Drawing

Package Code:NDG40P2 40-VFQFPN 5.0 x 5.0 x 0.9 mm Body, 0.4 mm Pitch PSC-4292-02, Revision: 02, Date Created: Aug 30, 2022

RENESAS

Package Outline Drawing

Package Code:NDG28P1 28-VFQFPN 4.0 x 4.0 x 0.9 mm Body, 0.4mm Pitch PSC-4249-01, Revision: 02, Date Created: Feb 06, 2024

Package Outline Drawing

Package Code:NDG20P2 20-VFQFPN 3.0 x 3.0 x 0.9 mm Body, 0.4mm Pitch PSC-4179-02, Revision: 02, Date Created: Jan 29, 2024

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